

Freeform Search

Database:	US Pre-Grant Publication Full-Text Database US Patents Full-Text Database US OCR Full-Text Database EPO Abstracts Database JPO Abstracts Database Derwent World Patents Index IBM Technical Disclosure Bulletins
Term:	L18 and (sample\$1 or specimen\$1)
Display:	10 Documents in Display Format: - Starting with Number 1
Generate: <input type="radio"/> Hit List <input checked="" type="radio"/> Hit Count <input type="radio"/> Side by Side <input type="radio"/> Image	

Search History

DATE: Thursday, June 23, 2005 [Printable Copy](#) [Create Case](#)

Set Name Query

side by side

Hit Count Set Name

result set

DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ

<u>L19</u>	L18 and (sample\$1 or specimen\$1)	143	<u>L19</u>
<u>L18</u>	L14 and (test\$3)	429	<u>L18</u>
<u>L17</u>	(switch\$3) and (accurate resistance meter)	0	<u>L17</u>
<u>L16</u>	(switch\$3) and (precision resistance meter)	0	<u>L16</u>
<u>L15</u>	(electronic switch\$3) same(resistance meter)	6	<u>L15</u>
<u>L14</u>	(switch\$3) and (resistance meter)	855	<u>L14</u>
<u>L13</u>	(switch\$3) and (accurate ohmmeter)	3	<u>L13</u>
<u>L12</u>	(electronic switch\$3) same (precision rheostat)	0	<u>L12</u>
<u>L11</u>	(switch\$3) and (calibrat\$3 ohmmeter)	12	<u>L11</u>
<u>L10</u>	(switch\$3) and (precision ohmmeter)	5	<u>L10</u>
<u>L9</u>	(electronic switch\$3) and (precision ohmmeter)	2	<u>L9</u>

DB=USPT; PLUR=YES; OP=ADJ

<u>L8</u>	L7 and (probe\$1)	1	<u>L8</u>
<u>L7</u>	L6 and "ohmmeter"	1	<u>L7</u>
<u>L6</u>	4092591.pn.	1	<u>L6</u>

DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ

<u>L5</u>	(electronic switch\$3) same (ohmmeter)	15	<u>L5</u>
<u>L4</u>	(switch\$3 or multiplexer or multiplexor) same (precision ohmmeter)	3	<u>L4</u>
<u>L3</u>	(switch\$3 or multiplexer or multiplexor) same (ohmmeter)	560	<u>L3</u>
<u>L2</u>	(switch\$3 network) and (precision ohmmeter)	1	<u>L2</u>
<u>L1</u>	(switch\$3 network) same (precision ohmmeter)	1	<u>L1</u>

END OF SEARCH HISTORY

Freeform Search

Database:	US Pre-Grant Publication Full-Text Database US Patents Full-Text Database US OCR Full-Text Database EPO Abstracts Database JPO Abstracts Database Derwent World Patents Index IBM Technical Disclosure Bulletins
Term:	L4 and (test\$3 apparatus)
Display:	10 Documents in <u>Display Format</u> : - Starting with Number 1
Generate: <input type="radio"/> Hit List <input checked="" type="radio"/> Hit Count <input type="radio"/> Side by Side <input type="radio"/> Image	

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<u>Set Name</u>	<u>Query</u>	<u>Hit Count</u>	<u>Set Name</u>
side by side			result set
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ</i>			
<u>L9</u>	L4 and (test\$3 apparatus)	80	<u>L9</u>
<u>L8</u>	L4 and (test\$3 chamber)	7	<u>L8</u>
<u>L7</u>	L4 and (plurality chips)	3	<u>L7</u>
<u>L6</u>	L4 and (plurality IC or plurality components)	2	<u>L6</u>
<u>L5</u>	L4 and (plurality samples or plurality specimens)	17	<u>L5</u>
<u>L4</u>	L3 and (connect\$4)	879	<u>L4</u>
<u>L3</u>	(switch\$3) same (ohmmeter or resistance meter)	953	<u>L3</u>
<u>L2</u>	swicth\$3 ohmmeter	0	<u>L2</u>
<u>L1</u>	switch\$3 compris\$3 ohmmeter	0	<u>L1</u>

END OF SEARCH HISTORY